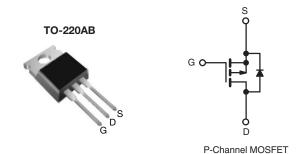


# **Power MOSFET**

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	- 200			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = - 10 V	1.5		
Q <sub>g</sub> (Max.) (nC)	22			
Q <sub>gs</sub> (nC)	12			
Q <sub>gd</sub> (nC)	10			
Configuration	Single			



#### **FEATURES**

- Dynamic dV/dt Rating
- P-Channel
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





#### **DESCRIPTION**

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220AB package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220AB contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION		
Package	TO-220AB	
Load (Dh.) frag	IRF9620PbF	
Lead (Pb)-free	SiHF9620-E3	
SnPb	IRF9620	
SIFD	SiHF9620	

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	- 200	V	
Gate-Source Voltage			$V_{GS}$	± 20	V	
Continuous Drain Current	V <sub>GS</sub> at - 10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	- 3.5	A	
		T <sub>C</sub> = 100 °C		- 2.0		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	- 14	1	
Linear Derating Factor				0.32	W/°C	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		P <sub>D</sub>	40	W	
Peak Diode Recovery dV/dt <sup>b</sup>			dV/dt	- 5.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	00	
Soldering Recommendations (Peak Temperature)	for 10 s			300°	- °C	
	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $I_{SD} \le$  3.5 A, dI/dt  $\le$  95 A/µs,  $V_{DD} \le V_{DS},\, T_J \le$  150 °C.
- c. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	3.1		

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static		<u>.</u>					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = - 250 μA		- 200	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = - 1 mA		- 0.22	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = '	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = - 250 μA		-	- 4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	\	V <sub>GS</sub> = ± 20 V		-	± 100	nA
Zana Oata Waltana Duain Ourmant		V <sub>DS</sub> = - 200 V, V <sub>GS</sub> = 0 V		-	-	- 100	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 160 V	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	- 500	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V	I <sub>D</sub> = - 1.5 A <sup>b</sup>	-	-	1.5	Ω
Forward Transconductance	9fs	V <sub>DS</sub> = -	V <sub>DS</sub> = - 50 V, I <sub>D</sub> = - 1.5 A <sup>b</sup>		-	-	S
Dynamic		<u>.</u>					
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = -25 \text{ V},$ f = 1.0  MHz,  see fig. 5		-	350	-	pF
Output Capacitance	C <sub>oss</sub>			-	100	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	30	-	
Total Gate Charge	Qg			-	-	22	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = -10 \text{ V}$ $I_D = -4.0 \text{ A}, V_{DS} = -160 \text{ V},$ see fig. 11 and 18 <sup>b</sup>	-	-	12	nC	
Gate-Drain Charge	Q <sub>gd</sub>	1	see lig. 11 and 10	-	-	10	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = - 100 V, $I_D$ = - 1.5 A, $R_g$ = 50 $\Omega$ , $R_D$ = 67 $\Omega$ , see fig. 17 <sup>b</sup>		-	15	-	- ns
Rise Time	t <sub>r</sub>			-	25	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	20	-	
Fall Time	t <sub>f</sub>			-	15	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s	<u>.</u>					
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		ı	-	- 3.5	_
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	- 14	A
Body Diode Voltage	$V_{SD}$	T <sub>J</sub> = 25 °C, I <sub>S</sub> = - 3.5 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	-	- 7.0	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	- T <sub>J</sub> = 25 °C, I <sub>F</sub> = - 3.5 A, dl/dt = 100 A/μs <sup>b</sup>		-	300	450	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	1.9	2.9	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )				L <sub>D</sub> )	

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq 300~\mu s;$  duty cycle  $\leq 2~\%.$



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

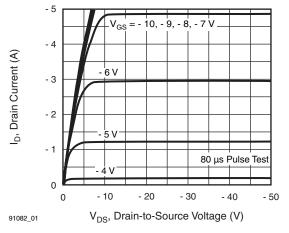


Fig. 1 - Typical Output Characteristics

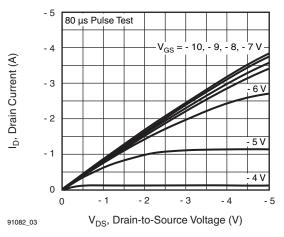


Fig. 3 - Typical Saturation Characteristics

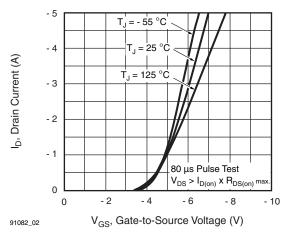


Fig. 2 - Typical Transfer Characteristics

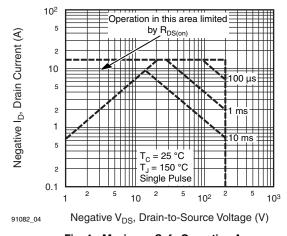


Fig. 4 - Maximum Safe Operating Area

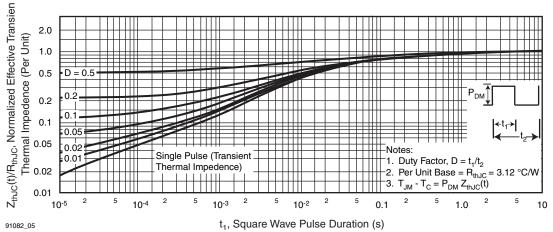


Fig. 5 - Maximum Effective Transient Thermal Impedance, Junction-to-Case vs. Pulse Duration



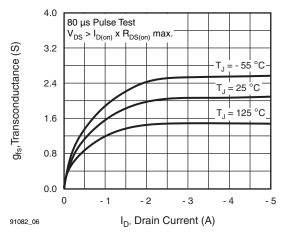


Fig. 6 - Typical Transconductance vs. Drain Current

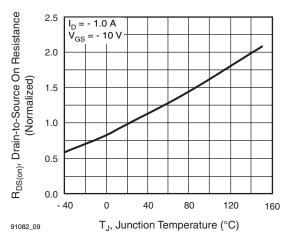


Fig. 9 - Normalized On-Resistance vs. Temperature

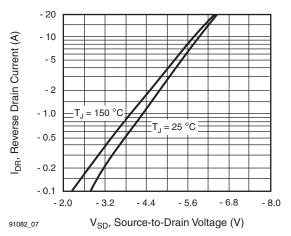


Fig. 7 - Typical Source-Drain Diode Forward Voltage

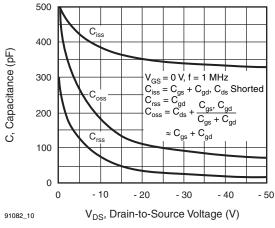


Fig. 10 - Typical Capacitance vs. Drain-to-Source Voltage

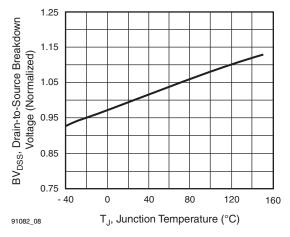


Fig. 8 - Breakdown Voltage vs. Temperature

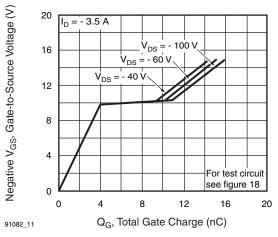


Fig. 11 - Typical Gate Charge vs. Gate-to-Source Voltage



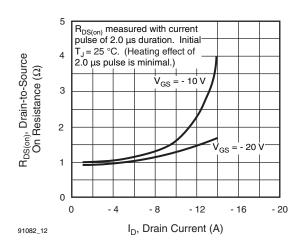


Fig. 12 - Typical On-Resistance vs. Drain Current

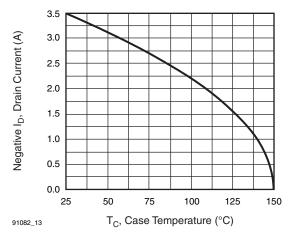


Fig. 13 - Maximum Drain Current vs. Case Temperature

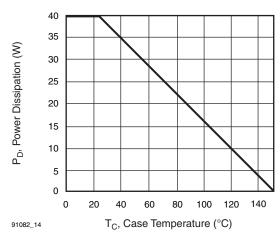


Fig. 14 - Power vs. Temperature Derating Curve

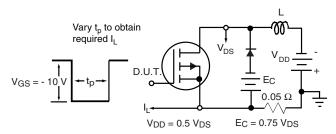


Fig. 15 - Clamped Inductive Test Circuit

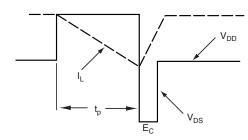


Fig. 16 - Clamped Inductive Waveforms

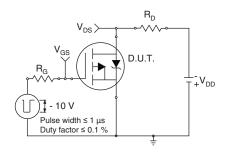


Fig. 17a - Switching Time Test Circuit

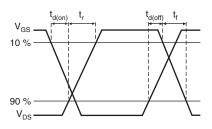


Fig. 17b - Switching Time Waveforms



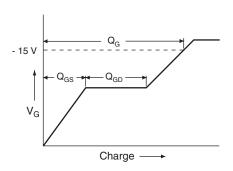


Fig. 18a - Basic Gate Charge Waveform

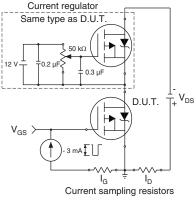
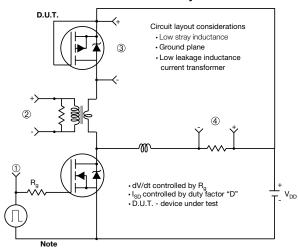


Fig. 18b - Gate Charge Test Circuit

#### Peak Diode Recovery dV/dt Test Circuit



Compliment N-Channel of D.U.T. for driver

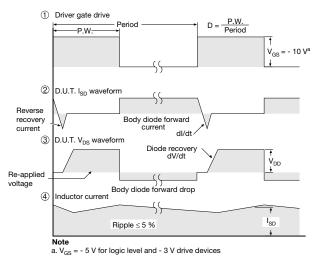


Fig. 19 - For P-Channel

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